ESD problems are increasing in the electronics industry because of the trends towards higher speed and smaller device sizes. EOS/ESD Association, Inc. has been a leader in ESD protection and control mitigation. To improve your knowledge EOS/ESD Association, Inc. is pleased to offer a NEW Manufacturing track at the 2017 EOS/ESD Symposium.

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Hands-on Sessions Designed to enhance your understanding of the instruments and measurements used in ESD control. For these sessions, equipment and demonstrations will be available for your preview and practice. What better way to understand solutions to your problems than to have an expert show you how to solve complex issues and give you the opportunity to try it for yourself!

Discussion Group Sessions Discuss, participate, and engage with your peers and group leaders to delve into key topics in our industry.

Short Tutorial Sessions Participate in tutorials that are designed to be focused learning opportunities on relevant subjects.

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Setting the Global Standards for Static Control!
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Hands-on Sessions
I Measurement in ESD Control Standards
Moderator: Dale Parkin, Seagate Technology; Wolfgang Stadler, Intel Deutschland GmbH
II.A How to Detect ESD Events by EMI (ESD Event Detectors, Antenna, and Scope)?
Moderator: TBD
II.B Detecting and Solving EMI Problems in Manufacturing
Moderator: Vladimir Kraz, OnFILTER, Inc.
II.C Measuring Grounds in a Facility
Moderator: Jay Skolnik, Skolnik Technical Training
II.D ESD Field Measurement Pitfalls and ESD Voltage Suppression Demonstration (ANSI/ESD S20.20 and IEC61340-5-1 Differences)
Moderator: Ted Dangelmayer, Dangelmayer Associates, LLC

Short Tutorial Sessions
I.A Cable Discharge Events in Assembly and Testing
Reinhold Gaertner, Infineon Technologies
I.B Charged Board Event and the Correlation to Charged Device Model
Pasi Tamminen, EDR&Medeso
I.C Standard Practice on Proposed New Ionizer Measurement Methods
Arnold Steinman, Electronics Workshop
II.A Packages, Tape & Reel, Trays, and Others: How to Assess ESD Compliance?
David E. Swenson, Affinity Static Control Consulting, LLC
II.B Introduction to Shielding Bag Test – ANSI/ESD STM11.31
Dale Parkin, Seagate Technology; Ron Gibson, Advanced Static Control Consulting
II.C “Meet the Standard” with History, Background, and Contents
Matt Strickland, L3 Technologies, Inc.; Ted Dangelmayer, Dangelmayer Associates LLC

Discussion Group Sessions
DG.A CDM Controls for Class 0
Moderator: Ted Dangelmayer, Dangelmayer Associates, LLC
DG.B Electrical Overstress in Manufacturing – Mitigation Strategies and Standards
Moderators: Scott Ward, Texas Instruments, Inc.; Terry Welsher, Dangelmayer Associates, LLC
DG.C ESD Control Program Management for Contract Manufacturing
Moderator: Charles McClain, Micron Technology, Inc.

Invited Speaker Sessions
I: Beyond S20.20: Explosives
Jay Skolnik, Skolnik Technical Training
II: IoT Challenges for Manufacturing
Michelle Lam, IBM; Terry Welsher, Dangelmayer Associates, LLC

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